TRANSISTOR | MOS-FET | ZENER DIODE | PHOTO TRANSISTOR

# SEMICONDUCTOR TEST SYSTEM 半導体テストシステム

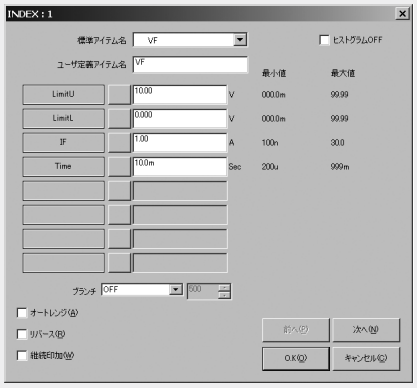
# CCT510NA 500V 10A

3-MULTIPLEXER

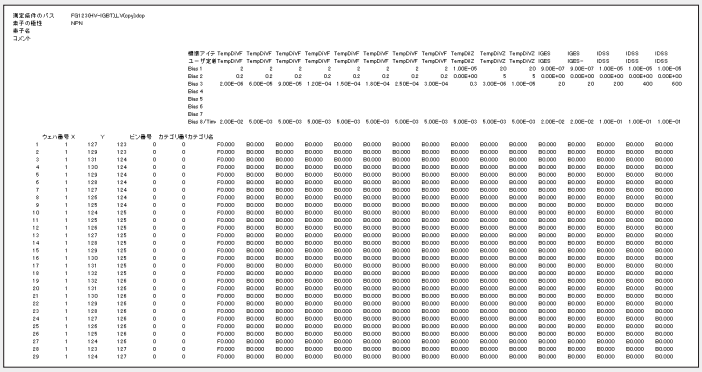
●CCT510NA is DC tester for production line which can measure up to 3 stations. Also, computer can control 8 testers at maximum, it means that 24 stations can be controlled by one computer.

●CCT510NAは生産ライン用として開発されたDCテスターで、3ステーションまでの測定を可能としています。また、パソコンからのコントロールはテスター8台まで可能なため、最大24ステーションの測定が1台のパソコンから制御できます。

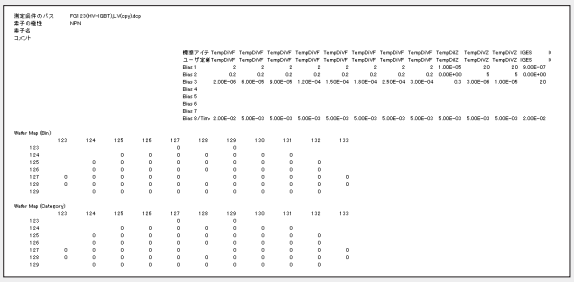
*Software Display*




[Indication example of measurement data by log format]
[ログ形式 測定データ表示例]



[Indication example of summary map data] [サマリーマップデータ表示例]



| MODEL | CCT510NA |
|---|---|
| SOFTWARE | |
| TEST PROGRAM | TBS(TEST-BY-SORT) Test symbol names can be changed／Host CPU interfaceable by RS-232C |
| TEST PLAN/SORT PLAN | 100/100 |
| BIN OUT | 24 |
| DC UNIT | |
| TEST DEVICES | Transistor, MOS-FET, Zener Diode, Photo Transistor |
| VOLTAGE | 500V |
| CURRENT | 9.99A |
| TEST ITEMS | |
| TRANSISTOR | ICE, ICB, IEB, ILCE, ILCB, ILEB, BVCE, BVCB, BVEB, IB, HFE, IC, HFEC, VCESAT, VBESAT, VFBC, VFBE, VFEC, BTON |
| MOS-FET | IDS, IDG, IGSX, IGSS, ISG, IGDL, BVDS, BVDG, BVSG, VFGD, VFGS, VFSDS, VP, VTH, VDSON(RDSON), IDON, HIDSS, GMP, GMV, GMI |
| ZENER DIODE | VF, IF, VZ, IR, ZZ, ZZCB, ZZEB, RZ, RZCB, RZEB |
| PHOTO TRANSISTOR | VCEON, ICEL, PO, IROPT, BVROPT |
| DIMENSIONS & WEIGHT | |
| MAIN UNIT | 430(W)×700(D)×245(H)…41kg |
| HEAD BOX | 135(W)×350(D)×235(H)…7kg(1set) |